

<b>Notic of References Cited</b>	Application/Control No. 10/621,372	Applicant(s)/Pat nt Under Reexamination AKIYAMA ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,590,134	05-1986	Warszawski et al.	429/35
*	B	US-6,533,827	03-2003	Cisar et al.	29/623.4
*	C	US-6,635,378	10-2003	Yang et al.	429/34
*	D	US-2002/0187384	12-2002	Kato et al.	429/35
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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